

Description

The VSM80N06 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

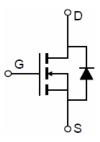
General Features

- V_{DS} =60V, I_D =80A $R_{DS(ON)}$ =6.5m Ω (typical) @ V_{GS} =10V $R_{DS(ON)}$ =7.5m Ω (typical) @ V_{GS} =4.5V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- PWM
- Load Switching





Schematic Diagram

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|----------|----------------|-----------|------------|----------|
| VSM80N06-TC | VSM80N06 | TO-220C | - | - | - |

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

| Parameter | Symbol | Limit | Unit | |
|--|-----------------------|------------|------------|--|
| Drain-Source Voltage | V _{DS} | 60 | V | |
| Gate-Source Voltage | V _G s | ±20 | V | |
| Drain Current-Continuous | I _D | 80 | А | |
| Drain Current-Continuous(T _C =100°ℂ) | I _D (100℃) | 56.5 | Α | |
| Pulsed Drain Current | I _{DM} | 320 | Α | |
| Maximum Power Dissipation | P _D | 110 | W | |
| Derating factor | | 0.73 | W/℃ | |
| Single pulse avalanche energy (Note 5) | E _{AS} | 390 | mJ | |
| Operating Junction and Storage Temperature Range | T_{J} , T_{STG} | -55 To 175 | $^{\circ}$ | |



Shenzhen VSEEI Semiconductor Co., Ltd

Thermal Characteristic

Electrical Characteristics (T_C=25°Cunless otherwise noted)

| Parameter | Symbol | Condition | Min | Тур | Max | Unit | | |
|------------------------------------|---|--|-----|------|------|------|--|--|
| Off Characteristics | • | | • | | | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} V _{GS} =0V I _D =250µA | | 60 | - | - | V | | |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} =60V,V _{GS} =0V | - | - | 1 | μA | | |
| Gate-Body Leakage Current | I _{GSS} | V _{GS} =±20V,V _{DS} =0V | - | - | ±100 | nA | | |
| On Characteristics (Note 3) | • | | • | | | | | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}$, $I_{D}=250\mu A$ | 0.8 | 1.3 | 1.8 | V | | |
| Dunin Course On State Desigtance | R _{DS(ON)} | V _{GS} =10V, I _D =20A | - | 6.5 | 8.0 | mΩ | | |
| Drain-Source On-State Resistance | | V _{GS} =4.5V, I _D =20A | - | 7.5 | 9.5 | mΩ | | |
| Forward Transconductance | g FS | V _{DS} =5V,I _D =20A | 20 | - | - | S | | |
| Dynamic Characteristics (Note4) | - | | • | | | • | | |
| Input Capacitance | C _{lss} | \/ -20\/\/ -0\/ | - | 4000 | - | PF | | |
| Output Capacitance | Coss | V_{DS} =30V, V_{GS} =0V, | - | 290 | - | PF | | |
| Reverse Transfer Capacitance | C _{rss} | F=1.0MHz | - | 210 | - | PF | | |
| Switching Characteristics (Note 4) | - | | • | | | • | | |
| Turn-on Delay Time | t _{d(on)} | | - | 8.5 | - | nS | | |
| Turn-on Rise Time | t _r | V_{DD} =30V, R_L =1 Ω | - | 7 | - | nS | | |
| Turn-Off Delay Time | t _{d(off)} | V_{GS} =10 V , R_{G} =3 Ω | - | 40 | - | nS | | |
| Turn-Off Fall Time | t _f | | - | 15 | - | nS | | |
| Total Gate Charge | Qg | \/ 00\/ L 00A | - | 90.3 | | nC | | |
| Gate-Source Charge | Q_{gs} | V _{DS} =30V,I _D =20A, | - | 10.9 | | nC | | |
| Gate-Drain Charge | Q_{gd} | V _{GS} =10V | - | 20.6 | | nC | | |
| Drain-Source Diode Characteristics | - | | • | | | • | | |
| Diode Forward Voltage (Note 3) | V _{SD} | V _{GS} =0V,I _S =20A | - | | 1.2 | V | | |
| Diode Forward Current (Note 2) | Is | | - | - | 80 | А | | |
| Reverse Recovery Time | t _{rr} | TJ = 25°C, IF = 20A | - | 32 | - | nS | | |
| Reverse Recovery Charge | Qrr | di/dt = 100A/µs ^(Note3) | - | 45 | - | nC | | |
| Forward Turn-On Time | t _{on} | Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD) | | | | | | |

Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width $\leq 300 \mu s$, Duty Cycle $\leq 2\%$.
- **4.** Guaranteed by design, not subject to production
- **5.** E_{AS} condition : Tj=25 $^{\circ}\text{C}$,V_{DD}=30V,V_G=10V,L=0.5mH,Rg=25 Ω

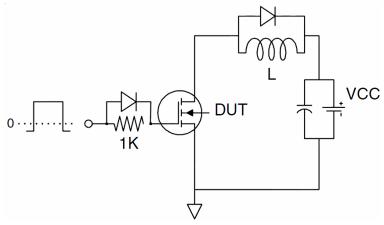


Test circuit

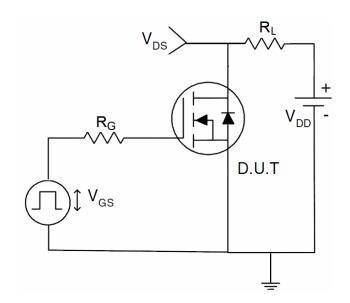
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

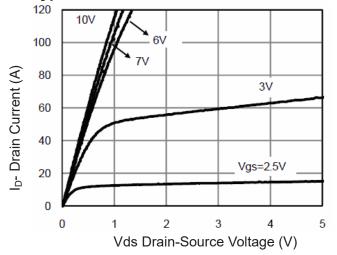


Figure 1 Output Characteristics

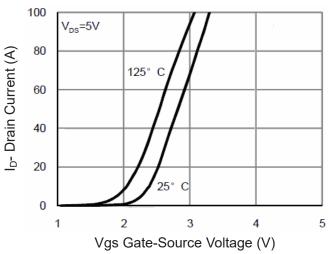


Figure 2 Transfer Characteristics

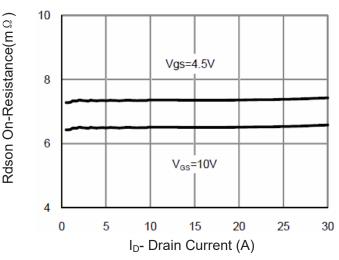


Figure 3 Rdson-Drain Current

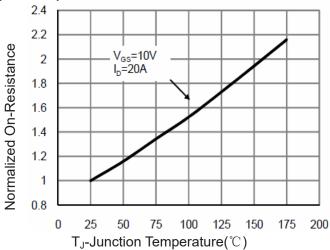


Figure 4 Rdson-JunctionTemperature

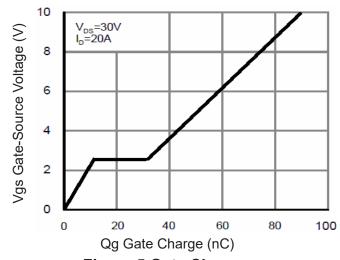


Figure 5 Gate Charge

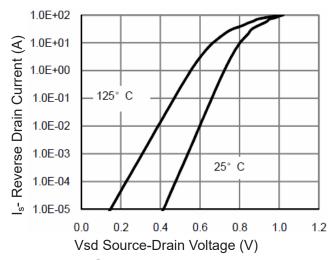
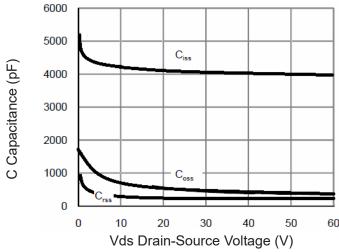


Figure 6 Source- Drain Diode Forward



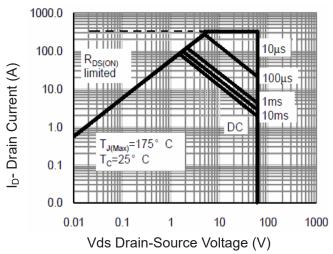
v1.0



120 100 Power Dissipation (W) 80 60 40 20 0 0 50 75 100 125 150 175 T_J-Junction Temperature (°C)

Figure 7 Capacitance vs Vds

Figure 9 Power De-rating



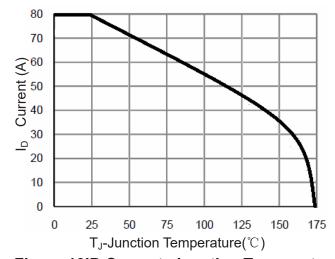
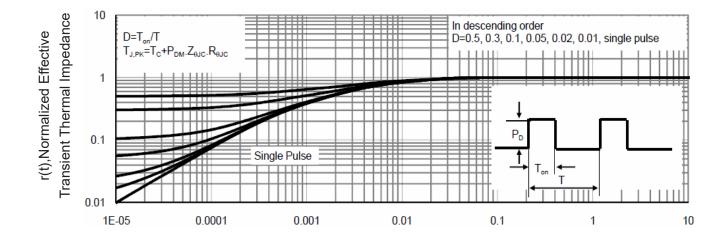


Figure 8 Safe Operation Area

Figure 10ID Current- Junction Temperature

http://www.vseei.com/



Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance

Page 5